

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: To Be Assigned
Examiner: To Be Assigned

INVENTOR PATENT APPLICATION of

Applicant(s) : Hiroomi TSUTAE)

Appln. No. : To Be Assigned)

Filed : September 9, 2003)

For : PROCESS OF CLEANING A SEMICONDUCTOR)
MANUFACTURING SYSTEM AND METHOD)
OF MANUFACTURING A SEMICONDUCTOR)
DEVICE)

Atty. Dkt. : FUJI 136)

**INFORMATION
DISCLOSURE
STATEMENT**

Commissioner for Patents
Washington, D.C. 20231


Sir:

This is an information disclosure statement submitted in compliance with the timing requirements of 37 C.F.R. §1.97(b)(1).

Attached are copies of three Japanese patent publications. The relevance of the publications can be gleaned from the attached English-language Abstract, and from pages 2 and 3 of the specification, where these documents are discussed. The publications are listed on the attached Form PTO-1449.

Since this Information Disclosure Statement is being filed with the application, no certification or fee is required, and the requirements of 37 C.F.R. §§1.97 and 1.98 are deemed to be fully met as to the document submitted. Consideration of the submitted document is respectfully requested.

Respectfully submitted,


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September 9, 2003
Date

SMR/tl

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FORM PTO-1449 INFORMATION DISCLOSURE STATEMENT			Atty Docket <div style="text-align: center;">FUJI 136</div>		Application No. <div style="text-align: center;">To Be Assigned</div>		
			Applicant <div style="text-align: center;">Hiroomi TSUTAE</div>				
			Filing Date <div style="text-align: center;">September 9, 2003</div>		Group Unit <div style="text-align: center;">To Be Assigned</div>		
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub- Class	Filing Date
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Sub- Class	Trans- lation
	AL	07-201738	08/04/95	Japan			Abstract
	AM	09-249976	09/22/97	Japan			Abstract
	AN	10-147877	06/02/98	Japan			Abstract
	AO						
OTHER (Including Author, Title, Date, Pertinent Pages, etc.)							
	AP						
Examiner					Date Considered		
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							